

<b>Notice of References Cited</b>	Application/Control No. 10/729,919	Applicant(s)/Patent Under Reexamination HSIANG, YUEH WEN	
	Examiner Kimnhung Nguyen	Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0011576	01-2003	Sandbach et al.	345/173
*	B	US-5,565,657	10-1996	Merz, Eric A.	178/18.01
*	C	US-5,724,064	03-1998	Stefik et al.	345/105
*	D	US-2003/0107556	06-2003	Yamashita, Shunichi	345/173
*	E	US-2004/0027340	02-2004	Muraoka et al.	345/173
*	F	US-2003/0206161	11-2003	Liu et al.	345/173
*	G	US-2003/0071796	04-2003	Nakanishi et al.	345/173
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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